


<b>Search Notes</b>  	<b>Application/Control No.</b>  10534337	<b>Applicant(s)/Patent Under Reexamination</b>  MEYER ET AL.
	<b>Examiner</b>  Nikki H Dees	<b>Art Unit</b>  1794

SEARCHED			
Class	Subclass	Date	Examiner
426	249, 250, 516	06/13/2008	nhd

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor search in eDAN	06/12/2008	nhd
EAST search history attached	06/13/2008	nhd

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner